Docket No.: P2000,0361

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Date: August 15, 2005

UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.

10/609,464

Confirmation No: 7300

Applicant

Wolfgang Dickenscheid, et al.

Filed

June 27, 2003

Title

Method for Characterizing and Simulating a Chemical

Mechanical Polishing Process

Art Unit

2125

Examiner

Kidest Bahta

Docket No.

P2000,0361

Customer No.:

24131

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97(i)

Hon. Commissioner for Patents

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following publications are submitted herewith:

1997 Proceedings Second International Chemical-Mechanical Polish (C.M.P.) for ULSI Multilevel Interconnection Conference (CMP-MIC). "A Mechanical Model for Dram Dielectric Chemical-Mechanical Polishing Process." Catalog No. 97ISMIC-200P, Library of Congress No. 89-644090, February 13-14, 1997, Santa Clara, CA, pp. 259-265.

It is believed that the enclosed prior art is less pertinent than the prior art previously submitted and cited by the Examiner. Kindly place the references in the Patent Office file wrapper. <u>UNDER 37 C.F.R. 1.97(i)</u>

Respectfully submitted,

For Maplicants

Date: August 15, 2005

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FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE				Attorney Docket No.: Applic. No. 10/609,464				
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		(CMP-MIC). "A Mechanical Model for Dram Dielectric Chemical-Mechanical Polishing Process." Catalog No. 97ISMIC-200P,						
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		Clara, CA, pp. 2	259-265.					
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with								
next communication to applicant.								